Abstracts

Coupling Phenomena in Conductor-Backed Slotline Structures

Y. Liu, T. Hirota and T. Itoh. "Coupling Phenomena in Conductor-Backed Slotline Structures." 1993 MTT-S International Microwave Symposium Digest 93.3 (1993 Vol. III [MWSYM]): 1203-1206.

Leakage phenomena possible in conductor-backed slotlines were investigated through an analysis of coupled slotlines for possible application for a non-proximity directional coupler. Obtained propagation constants and experimental results confirm that coupling is caused by leakage through the conductor backing. It was found that the leakage can be controlled by a modification of the structures.

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